
Editorial

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Enhancing the surface finish and integrity of engineered components is in increasing demand, particularly for the workparts used in electronic and optical devices and systems. Significant progress has been made in recent years to develop new and advanced surface finishing technologies as well as to understand the surface finishing technologies in order to adequately predict, control and optimise the surface finishing processes in practice. The aim of this special issue of the IJCAT is to compile the state-of-the-art in surface finishing technologies.

This special issue contains papers selected from the submissions to the International Conference on Surface Finishing Technology and Surface Engineering (ICSFT 2006) held in Dalian, China, from 24 to 27 September 2006. All the papers included in this special issue have gone through a rigorous peer-review and revision process for their originality and quality.

The topics covered in this special issue include:

- fundamental studies of surface finishing technologies

- advanced deburring techniques and theories
- advanced surface finishing techniques for advanced materials
- advanced abrasives and equipment for surface finishing processes
- characterisation of surface integrity.

This special issue is relevant not only to researchers, but also to postgraduate and final year undergraduate students, who are specialising in manufacturing engineering. In addition, it should be a valuable reference for practicing engineers in materials processing who are responsible for making the manufacturing operations more efficient and effective.

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